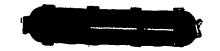


Application/Control No.	Applicant(s)/Patent under Reexamination
09/756,226	OOISHI, ISAMU
Examiner	Art Unit
Quoc A. Tran	2176

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Class	Subclass	Date	Examiner	
715	501	3/10/2006	20	
715	513	3/10/2006	X	
707	1	3/10/2006	m	
707	104.1	3/10/2006	X	

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
EAST (US-PAT, US-PGPUB, EPO, JPO, DERWENT, IBM_TDB) see Search Histoty Printout	3/10/2006			
ACM Digital Library see Search Histoty Printout	3/10/2006	8		
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## **SEARCHED** Date Class Sub. Exmr. 3/27/04 542 ar. 501.1 540 535 312 220 225 227 .90 467 8/17/01

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